

Attorney's Docket No. 5308-157IP2

1762-B  
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Das et al.

Serial No.: 10/045,542

Filed: October 26, 2001

For: METHOD OF FABRICATING AN OXIDE LAYER ON A SILICON  
CARBIDE LAYER UTILIZING AN ANNEAL IN A HYDROGEN  
ENVIRONMENT

Confirmation No.: 3570

Group Art Unit: 1762

Examiner: Michael. E. Barr

Date: November 5, 2003

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)**

Sir:

Attached is a list of documents on form PTO-1449 together with a copy of each identified document. It is requested that these documents be considered by the Examiner and officially made of record in accordance with the provisions of 37 C.F.R. § 1.56 and Section 609 of the MPEP.

This Information Disclosure is submitted in accordance with 37 C.F.R. § 1.97(b)(4), before the mailing of a first action after the filing of a Request for Continued Examination under 37 C.F.R. § 1.114. Therefore, no fee is believed due. However, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to Deposit Account No. 50-0220.

Respectfully submitted,

Timothy J. O'Sullivan

Registration No. 35,632

**Customer No. 20792**

Myers Bigel Sibley & Sajovec

P. O. Box 37428

Raleigh, North Carolina 27627


Telephone: (919) 854-1400

Facsimile: (919) 854-1401

**Certificate of Mailing under 37 CFR 1.8**

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, PO Box 1450, Alexandria, VA 22313-1450 on November 5, 2003.

Traci A. Brown

<b>FORM PTO-1449 U.S. Department of Commerce</b> Patent and Trademark Office				Attorney Docket Number 5308-157IP2		Serial No. 10/045,542	
<b>LIST OF DOCUMENTS CITED BY APPLICANT</b> (Use several sheets if necessary)							
				Applicants: Das et al.			
				Filing Date: October 26, 2001		Group 1762	
<b>U. S. PATENT DOCUMENTS</b>							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
1	5,587,870	12/24/96	Anderson et al.	361	313		
2	5,877,045	3/2/99	Kapoor	438	151		
<b>FOREIGN PATENT DOCUMENTS</b>							
Document Number	Date	Country	Class	Subclass	Translation Yes   No		
3	WO99/63591	12/9/99	PCT				
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
4	Mutin, P. Herbert, "Control of the Composition and Structure of Silicon Oxycarbide and Oxynitride Glasses Derived from Polysiloxane Precursors," <i>Journal of Sol-Gel Science and Technology</i> . Vol. 14 (1999) pp. 27-38.						
5	del Prado et al. "Full Composition Range Silicon Oxynitride Films Deposited by ECR-PECVD at Room Temperatures," <i>Thin Solid Films</i> . Vol. 343-344 (1999) p. 437-440.						
6	Wang et al. "High Temperature Characteristics of High-Quality SiC MIS Capacitors with O/N/O Gate Dielectric," <i>IEEE Transactions on Electron Devices</i> . Vol. 47, No. 2, February 2000.						
7	International Search Report for PCT/US02/09393 dated 10/15/03.						

 EXAMINER  
 \*EXAMINER

DATE CONSIDERED

Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.